



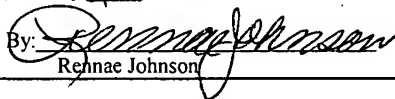
IFW

2829

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: KOIVUKANGAS et al. Examiner: Unassigned
Serial No.: 10/552,403 Group Art Unit: 2829
Filed: 10/07/2005 Docket No.: KOL.198.WUS
Title: METHOD AND ARRANGEMENT OF TESTING DEVICE IN MOBILE
STATION

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence and the papers, as described hereinabove, are being deposited in the United States Postal Service, as first class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on May 25, 2006.

By: 
Rennae Johnson

INFORMATION DISCLOSURE STATEMENT (37 C.F.R. §1.97(b))

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

With regard to the above-identified application, the items of information listed on the enclosed Form 1449 are brought to the attention of the Examiner.

This statement should be considered because it is submitted either within three months of the filing date or before the first Office Action of the above-identified application. Accordingly, no fee is due for consideration of the items listed on the enclosed Form 1449.

In accordance with 37 C.F.R. §1.98(a)(2), and the 05 August 2003 Official Gazette Notice, only a copy of each foreign document or non-U.S. patent/application listed on the enclosed Form 1449 is provided. One cited document, DE 198 41 470 A1, is a German patent not in the English language. However, pursuant to M.P.E.P. §609, an "X", "Y", or "A" indication may be used to provide the concise explanation of its relevance. Therefore, a counterpart European Search Report including such a relevance indication is provided herewith.

Please note that any notations or markings on the attached documents do not reflect particular relevance, or lack thereof, to the present application, nor were they necessarily made by anyone affiliated with the prosecution of the present application.

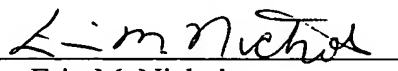
No representation is made that a reference is "prior art" within the meaning of 35 U.S.C. §§102 and 103 and Applicants reserve the right, pursuant to 37 C.F.R. §1.131 or otherwise, to establish that the reference(s) are not "prior art." Moreover, the Applicants do not represent that a reference has been thoroughly reviewed or that any relevance of any portion of a reference is intended.

Consideration of the items listed is respectfully requested. Pursuant to the provisions of M.P.E.P. §609, it is requested that the Examiner return a copy of the attached Form 1449, marked as being considered and initialed by the Examiner, to the undersigned with the next official communication.

Respectfully submitted,

HOLLINGSWORTH & FUNK, LLC
8009 34th Avenue South, Suite 125
Minneapolis, MN 55425
952.854.2700

Date: May 25, 2006

By: 
Erin M. Nichols
Reg. No. 57,125

FORM 149-E PATENT & TRADEMARK OFFICE MAY 31 2006	INFORMATION DISCLOSURE STATEMENT		Docket Number: KOL.198.WUS	Application Number: 10/552,403
	IN AN APPLICATION		Applicant: Koivukangas et al.	
	(Use several sheets if necessary)		Filing Date: 10/07/2005	Group Art Unit: 2829

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,481,186	01/02/1996	Heutmaker et al.			
	5,889,837	03/30/1999	Sands			
	6,118,982	09/12/2000	Ghisler et al.			
	6,404,293	06/11/2002	Darabi et al.			

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	0 525 941	02/03/1993	EP			X	
	0 759 680 A1	02/26/1997	EP			X	
	0 825 734 A2	02/25/1998	EP			X	
	198 41 470 A1	04/13/2000	DE				X
	01/63827 A1	08/30/2001	WO			X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
1997	Anthony P. Ambler, Moshe Ben Bassat and Louis Y. Ungar, "Economics of Diagnosis" Autotestcon, 97. 1997 IEEE Autotestcon Proceedings Ahanheim, CA, USA Sept. 22-25 1997, New York, NY USA, IEEE, pages 435 - 445. XP010253057 ISBN: 0-7803-4162-7.	
1999	Yervant Zorian, "Built-In-Self-Test", Microelectronic Engineering, Elsevier Publishers, BV., Amsterdam, NL, Vol. 49, no. 1-2, November 1999, pages 135-138. XP004182057, ISSN: 0167-9317.	
2001	Louis Y. Ungar et al., "IEEE-1149.X Standards: Achievements vs. Expectations", 2001 IEEE Autotestcon Proceedings. IEEE Systems Readiness Technology Conference. Autotestcon 2001, Valley Forge, PA, Aug. 20-23, 2001, IEEE Autotestcon Proceedings: IEEE Systems Readiness Technology Conference, New York, NY: IEEE, US, Vol. Conf. 37, XP 010556098, ISBN: 0-7803-7094-5.	
2001	Yue-Tsang Chen et al.: "Test Waveform Shaping in Mixed Signal Test Bus by Pre-Equalization", VLSI Test Symposium, 19 th IEEE Proceedings on VTS 2001 Apr 29 - 2001 May 3, Piscataway, NJ, USA, IEEE, 29 April 2001 (2001-04-29), pages 260-265, XP010542396 ISBN: 0-7695-1122-8.	
1994	Lu Y et al.: "Structure and Metrology for a Single-wire Analog Testability Bus", in Proceedings of the International Test Conference, Washington, Oct. 2 - 6, 1994, New York, IEEE, US, 2 October 1994 (1994-10-02), pages 919-928, XP000520055 ISBN: 0-7803-2103-0.	

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.	